Secondary Ion Mass Spectrometry: An Introduction to Principles and Practices
Paul van der Heide

**DESCRIPTION**

Serves as a practical reference for those involved in Secondary Ion Mass Spectrometry (SIMS)

- Introduces SIMS along with the highly diverse fields (Chemistry, Physics, Geology and Biology) to it is applied using up to date illustrations

- Introduces the accepted fundamentals and pertinent models associated with elemental and molecular sputtering and ion emission

- Covers the theory and modes of operation of the instrumentation used in the various forms of SIMS (Static vs Dynamic vs Cluster ion SIMS)

- Details how data collection/processing can be carried out, with an emphasis placed on how to recognize and avoid commonly occurring analysis induced distortions

- Presented as concisely as believed possible with All sections prepared such that they can be read independently of each other

**ABOUT THE AUTHOR**

Paul van der Heide is a recognized leader in surface analysis with emphasis on the application of Secondary Ion Mass Spectrometry (SIMS). This interest started during his PhD (completed in 1992 at the University of Auckland) which involved the design and construction of a magnetic sector SIMS instrument. Paul has since been heavily involved in the application and
development of SIMS at the University of Western Ontario, the University of Houston (where he also filled in various Professor level positions), Samsung Austin Semiconductor, and most recently at GlobalFoundries (NY). Paul has ~100 publications with this representing his 2nd book.

For additional product details, please visit https://www.wiley.com/en-us